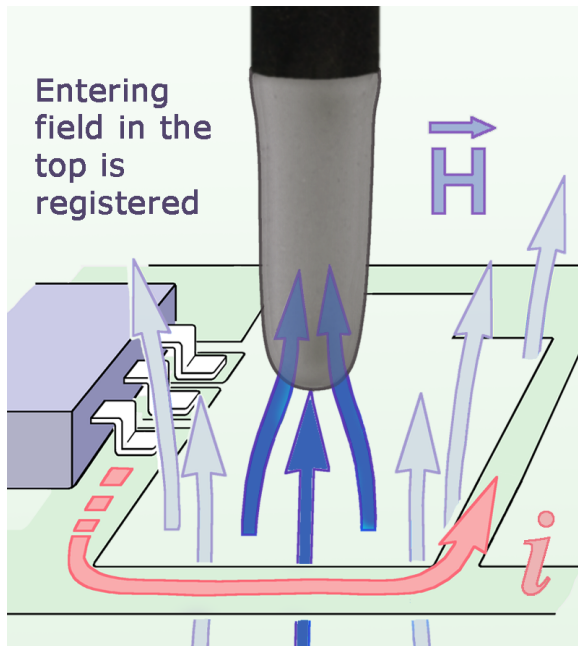


# XF-B 3-1

磁场探头 (30MHz-6GHz)



## Short description

XF-B 3-1型磁场探头的测量线圈相对垂直于探头柄。当探头竖直放置到电路板上时，其测量线圈直接平放在电路板的表面上。由此就能够测量到印刷电路板表面上很难达到的一些位置，如开关调节器的大元件之间的位置。

The XF-B 3-1 is a passive near-field probe which detects magnetic field lines emitted from the measured object at 90°. Magnetic field lines which enter the probe laterally are not detected.

In contrast to the XF-R 3-1 H-field probe, its coil is positioned in the probe tip at a 90° angle.

The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

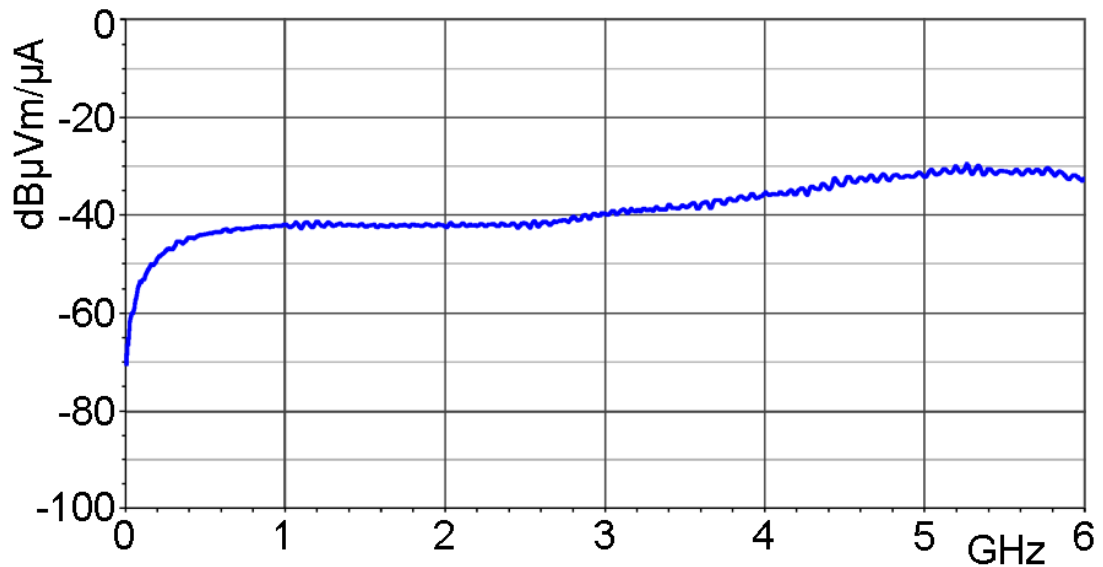
## Technical parameters

|      |                   |
|------|-------------------|
| 频率范围 | 30 MHz ... 6 GHz  |
| 分辨率  | ≈ 2 mm            |
| 探头尺寸 | Ø ≈ 4 mm          |
| 输出接口 | SMA, female, jack |
| 重量   | 15 g              |

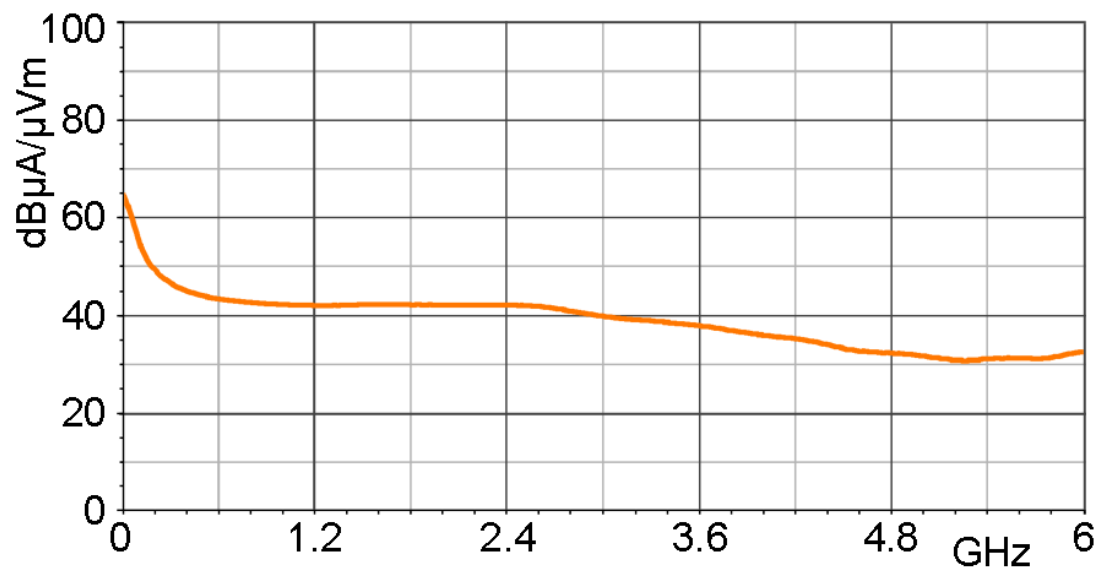
# XF-B 3-1

磁场探头 (30MHz-6GHz)

频率特性 [dB $\mu$ V] / [dB $\mu$ A/m]



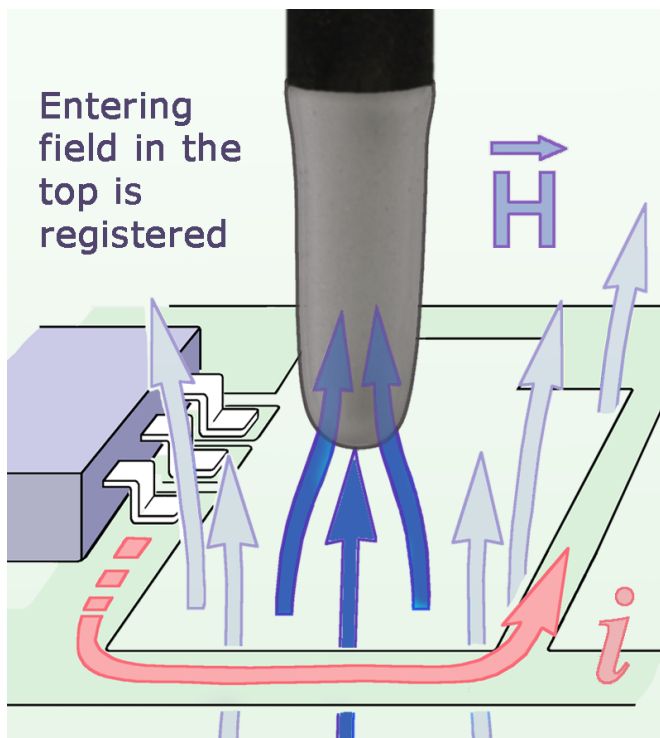
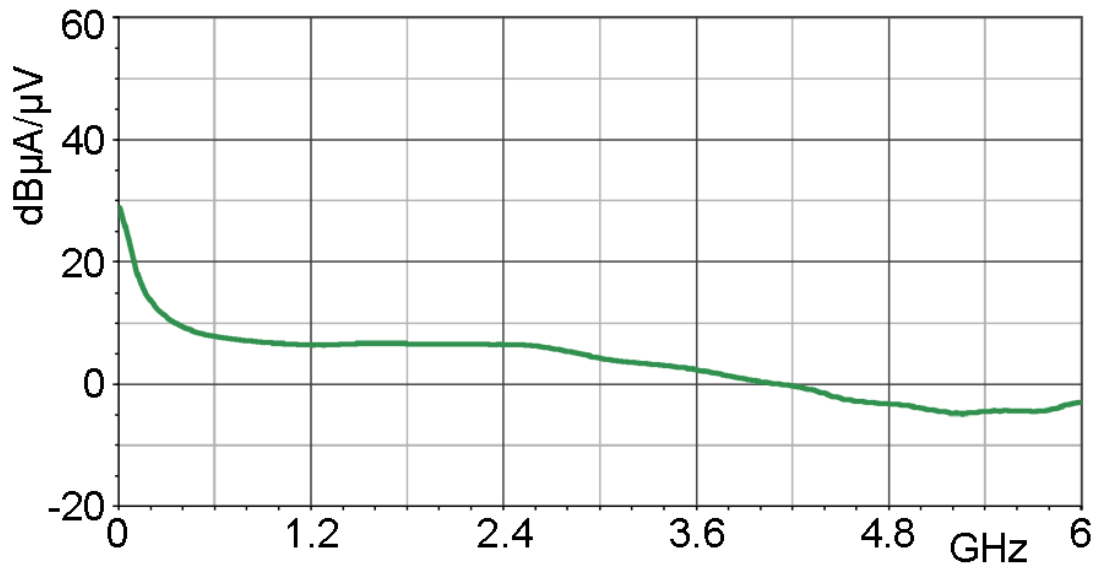
磁场校正曲线 [dB $\mu$ A/m] / [dB $\mu$ V]



# XF-B 3-1

磁场探头 (30MHz-6GHz)

电流校正曲线 [dB $\mu$ A] / [dB $\mu$ V]



# XF-B 3-1

磁场探头 (30MHz-6Hz)

Probe head

